

Receipt date: 06/29/2006

10/585079
AP20 Rec'd PCTO 29 JUN 2006

Docket No. 292853US2PCT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Hendrikus Petrus VAN DER LAAK, et al.

SERIAL NO: New U.S PCT Application Based on PCT/NL04/00922

GAU:

FILED: Herewith

EXAMINER:

FOR: METHOD, DEVICE AND DIFFRACTION GRATING FOR SEPARATING SEMICONDUCTOR ELEMENTS
FORMED ON A SUBSTRATE BY ALTERING SAID DIFFRACTION GRATING

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- ☒ The applicant(s) wish to make of record the references cited in the International Search Report and listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☐ Attached is a list of applicant's pending application(s), published application(s) or issued patent(s) which may be related to the present application. In accordance with the waiver of 37 CFR 1.98 dated September 21, 2004, copies of the cited pending applications are not provided. Cited published and/or issued patents, if any, are listed on the attached PTO form 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).


CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,
MAIER & NEUSTADT, P.C.
Marvin J. Spivak
Registration No. 24,913Customer Number
22850Tel. (703) 413-3000
Fax. (703) 413-2220
(OSMMN 05/03)Surinder Sachar
Registration No.34,423

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /G.E./

Receipt date: 06/29/2006

AP20 Rec'd PCT/PTO 529 JUN 2006 3742

SHEET 1 OF 1

Form PTO 1419 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 292853US2PCT		SERIAL NO. 10/585079 Based on PCT/NL04/00922	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hendrikus Petrus VAN DER LAAK, et al.			
				FILING DATE Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
/G.E./	AA	6 635 849	10/21/03	OKAWA, Tatsuki et al.			
/G.E./	AB	5 633 735	05/27/97	HUNTER, Robert O. Jr. et al.			
/G.E./	AE	5 029 243	07/02/91	DAMMANN, Hans et al.			
/G.E./	AO	5 922 224	07/13/99	BROEKROELOFS, Jan C.E.			
	AE						
	AE						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
/G.E./	AO	01/37769	05/31/01	WO			NO
/G.E./	AP	0 679 469	11/02/95	EP(equivalent of US 6 008 914)			NO
/G.E./	AQ	02/094528	11/28/02	WO(equivalent of US 2001/035401)			NO
	AP						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner /Geoffrey Evans/				Date Considered 06/10/2010			

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /G.E./